Fitting of a Planar Line

 ${\rm A[E]4M33TDV}{-\!\!\!-\!\!3D}$ compute vision: labs.

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October, 2011^*

1 Maximum Likelihood Model Fitting

Given a set of measurements \mathcal{X} , a model l is estimated by maximising likelihood function

$$\boldsymbol{l}^* = \arg\max p(\mathcal{X}|\boldsymbol{l}) \,. \tag{1}$$

Hence the conditional probability of the measurements given the model $p(\mathcal{X}|l)$ must be known. Should also a prior probability p(l) of the model be known, the maximum a posteriori estimate can be found by maximising $p(\mathcal{X}|l)p(l)$ instead.

In the case of fitting a line to a set of points, the measurements consists of a set of n point locations, $\mathcal{X} = \{x_1, \ldots, x_n\}$ and the model l is an appropriate line representation. The conditional probability of the points given the line is derived in the next sections.

2 Trivial Example: Single Point Fitting

For the purpose of demonstration, a trivial example is considered first. The model l in (1) is a single point x. Given the point (Euclidean) coordinates, the measurement is modelled as this very point polluted by an isotropic Gaussian noise,

$$\boldsymbol{x}_i = \boldsymbol{x} + \boldsymbol{e}_i \,, \tag{2}$$

$$\boldsymbol{e}_{i} \sim p(\boldsymbol{e}_{i}) = \mathcal{N}(\boldsymbol{e}_{i}; \boldsymbol{0}, \boldsymbol{\Sigma}_{\mathbf{e}}), \quad \boldsymbol{\Sigma}_{\mathbf{e}} = \begin{bmatrix} \sigma_{e}^{2} & 0\\ 0 & \sigma_{e}^{2} \end{bmatrix}).$$
(3)

Thus the conditional probability of a single measurement is

$$p(\boldsymbol{x}_i|\boldsymbol{x}) = \mathcal{N}(\boldsymbol{x}_i - \boldsymbol{x}; \boldsymbol{\theta}, \boldsymbol{\Sigma}_{\mathbf{e}}) = \mathcal{N}(\boldsymbol{x}_i; \boldsymbol{x}, \boldsymbol{\Sigma}_{\mathbf{e}}) = \frac{1}{2\pi\sqrt{|\boldsymbol{\Sigma}_{\mathbf{e}}|}} e^{0.5(\boldsymbol{x}_i - \boldsymbol{x})^\top \boldsymbol{\Sigma}_{\mathbf{e}}^{-1}(\boldsymbol{x}_i - \boldsymbol{x})} = \frac{1}{2\pi\sigma_e^2} e^{\frac{1}{2\sigma_e^2}||\boldsymbol{x}_i - \boldsymbol{x}||^2}$$
(4)

The measurements are assumed to be independent, so the overall probability of the measurements is

$$p(\mathcal{X}|\boldsymbol{x}) = n! \prod_{i=1}^{n} p(\boldsymbol{x}_i|\boldsymbol{x}) = n! \prod_{i=1}^{n} \mathcal{N}(\boldsymbol{x}_i - \boldsymbol{x}; \boldsymbol{\theta}, \boldsymbol{\Sigma}_e), \qquad (5)$$

where the n! term is added since the order of the measurements does not matter.

The ML estimate of the point from the measurements is then

$$\boldsymbol{x}^{*} = \arg \max_{\boldsymbol{x}} p(\mathcal{X}|\boldsymbol{x}) = \arg \min_{\boldsymbol{x}} \left(-\log p(\mathcal{X}|\boldsymbol{x}) \right) = = \arg \min_{\boldsymbol{x}} \left\{ -\log(n!) + \sum_{i=1}^{n} \left(-\log \frac{1}{2\pi\sigma_{e}^{2}} + \frac{||\boldsymbol{x}_{i} - \boldsymbol{x}||^{2}}{2\sigma_{e}^{2}} \right) \right\} = \arg \min_{\boldsymbol{x}} \sum_{i=1}^{n} ||\boldsymbol{x}_{i} - \boldsymbol{x}||^{2}, \quad (6)$$

*Last revision: October 13, 2011

where a monotonous function (log) was applied and some constants were omitted. This simplification obviously does not affect the result, and transforms the original problem of likelihood maximisation into the sum-of-squared-errors (SSE) minimisation.

Note, that in this simple case the coordinate components x, y, \ldots are independent. Hence the minimiser of (6) is found in closed-form simply by laying the derivation according to each component of x equal zero,

$$\boldsymbol{\theta} = \frac{\partial}{\partial \boldsymbol{x}} \sum_{i=1}^{n} ||\boldsymbol{x}_{i} - \boldsymbol{x}^{*}||^{2} = \sum_{i=1}^{n} 2(\boldsymbol{x}^{*} - \boldsymbol{x}_{i}) = 2n\boldsymbol{x}^{*} - 2\sum_{i=1}^{n} \boldsymbol{x}_{i} \Rightarrow \boldsymbol{x}^{*} = \frac{1}{n} \sum_{i=1}^{n} \boldsymbol{x}_{i}.$$
 (7)

As expected, the ML estimate (in arbitrary number of dimensions) of the point under isotropic Gaussian noise is simply the mean of the set \mathcal{X} .

3 Model for Noisy Planar Line and ML Estimate

A normalised planar line $\mathbf{l} = (\mathbf{n}^{\top}, d)$ is given, where \mathbf{n} is normal vector. There is also direction vector \mathbf{u} , such that $\mathbf{u} \perp \mathbf{n}$. These two vectors forms a basis of line coordinates. A point $\tilde{\mathbf{x}}$ (exactly) lying on the line is created as

$$\tilde{\boldsymbol{x}}_i = \begin{bmatrix} \boldsymbol{u} & \boldsymbol{n} \end{bmatrix} \begin{bmatrix} t_i \\ -d \end{bmatrix}, \qquad (8)$$

where t is a parameter along a line. Note, that the Euclidean coordinates of points are used. The distribution of the parameter is chosen as

$$t_i \sim p(t_i) = \mathcal{N}(t_i; \mu_t, \sigma_t) \,. \tag{9}$$

The measurement x_i is the line point polluted by an isotropic Gaussian noise,

$$\boldsymbol{x}_i = \tilde{\boldsymbol{x}}_i + \boldsymbol{e}_i \,, \tag{10}$$

$$\boldsymbol{e}_{i} \sim p(\boldsymbol{e}_{i}) = \mathcal{N}(\boldsymbol{e}_{i}; \begin{bmatrix} 0\\0 \end{bmatrix}, \begin{bmatrix} \sigma_{e} & 0\\0 & \sigma_{e} \end{bmatrix}).$$
(11)

The noise can be expressed in the line coordinates as

$$\boldsymbol{e}_{i} = \begin{bmatrix} \boldsymbol{u} & \boldsymbol{n} \end{bmatrix} \begin{bmatrix} t_{i}^{e} \\ d_{i}^{e} \end{bmatrix}, \quad p_{e} \left(\begin{bmatrix} d_{i}^{e} \\ t_{i}^{e} \end{bmatrix} \right) = \mathcal{N}(d_{i}^{e}; 0, \sigma_{e}) \mathcal{N}(t_{i}^{e}; 0, \sigma_{e}), \quad (12)$$

and the measurement expressed in the line coordinates is then

$$\boldsymbol{x}_{i} = \begin{bmatrix} \boldsymbol{u} & \boldsymbol{n} \end{bmatrix} \begin{bmatrix} t_{i} + t_{i}^{e} \\ -d + d_{i}^{e} \end{bmatrix}.$$
(13)

This leads to (using transformation of probability by linear transformation with unit Jacobian)

$$p(\boldsymbol{x}_i|\boldsymbol{l},t_i) = p_e\left(\begin{bmatrix} \boldsymbol{u}^\top\\\boldsymbol{n}^\top \end{bmatrix} \boldsymbol{x}_i - \begin{bmatrix} t_i\\-d \end{bmatrix} \right) = \mathcal{N}(\boldsymbol{u}^\top \boldsymbol{x}_i - t_i; 0, \sigma_e) \mathcal{N}(\underbrace{\boldsymbol{n}^\top \boldsymbol{x}_i + d}_{d_i}; 0, \sigma_e).$$
(14)

Here the term $d_i = \mathbf{n}^{\top} \mathbf{x}_i + d$ represents the orthogonal distance of the point \mathbf{x}_i to the line \mathbf{l} . Now the probability $p(\mathbf{x}_i|\mathbf{l})$ is derived from the joint p.d.f. $p(\mathbf{x}_i, t_i|\mathbf{l})$ by marginalisation over t_i .

$$p(\boldsymbol{x}_{i}|\boldsymbol{l}) = \int_{-\infty}^{\infty} p(\boldsymbol{x}_{i}, t_{i}|\boldsymbol{l}) \, \mathrm{d}t_{i} = \int_{-\infty}^{\infty} p(\boldsymbol{x}_{i}|\boldsymbol{l}, t_{i}) \, p(t_{i}) \, \mathrm{d}t_{i} = \int_{-\infty}^{\infty} \mathcal{N}(\boldsymbol{u}^{\top}\boldsymbol{x}_{i} - t_{i}; 0, \sigma_{e}) \, \mathcal{N}(d_{i}; 0, \sigma_{e}) \, \mathcal{N}(t_{i}; \mu_{t}, \sigma_{t}) \, \mathrm{d}t_{i} =$$

$$= \mathcal{N}(d_i; 0, \sigma_e) \int_{-\infty}^{\infty} \mathcal{N}(t_i; -\boldsymbol{u}^{\top} \boldsymbol{x}_i, \sigma_e) \mathcal{N}(t_i; \mu_t, \sigma_t) \, \mathbf{d}t_i =$$

$$= \mathcal{N}(d_i; 0, \sigma_e) \frac{1}{\sqrt{2\pi(\sigma_e^2 + \sigma_t^2)}} e^{\frac{-(-\boldsymbol{u}^{\top} \boldsymbol{x}_i - \mu_t)^2}{2(\sigma_e^2 + \sigma_t^2)}}$$
(15)

(The last step with fruitful help of Maple solver.)

Now the variance σ_t is chosen much larger than the size of image, where the points are observed, the mean μ_t is chosen e.g. zero (assuming that origin is in the image centre). Then the exponent is close to zero, and the probability is approximately

$$p(\boldsymbol{x}_i|\boldsymbol{l}) \approx \gamma \mathcal{N}(d_i; 0, \sigma_e),$$
 (16)

where γ is some constant.

Again, the measurements are assumed to be independent, so the overall conditional probability of the measurements is

$$p(\mathcal{X}|\boldsymbol{l}) = n! \prod_{i=1}^{n} p(\boldsymbol{x}_i|\boldsymbol{l}) = n! \gamma^n \prod_{i=1}^{n} \mathcal{N}(d_i; 0, \sigma_e).$$
(17)

Finally, log is applied and unnecessary constants are omitted to form a log-likelihood to minimise. The ML estimate of the line from the measurements is then

$$l^* = \arg \max_{l} p(\mathcal{X}|l) = \arg \min_{l} \left(-\log p(\mathcal{X}|l) \right) = \arg \min_{l} \left\{ -\log(n!\gamma^n) + \sum_{i=1}^n \left(-\log \frac{1}{\sqrt{2\pi\sigma_e^2}} + \frac{d_i^2}{2\sigma_e^2} \right) \right\} = \arg \min_{x} \sum_{i=1}^n d_i^2.$$
(18)

Again, the original problem of likelihood maximisation is transformed into the sum-of-squared-errors (SSE) minimisation. There is no closed form solution of (18), some numerical approach must be used.

4 Model for Noisy Planar Line Points with Outliers.

The process that creates set of points for a given line l is modelled by following three random processes that participates on generating each planar point x_i .

1. Label generator. A label $L_i \in \{I, O\}$ determining if a point is inlier or outlier is randomly drawn.

$$L_i \sim p_L(L_i)$$
, $p_L(L_i = I) = \alpha \text{ (const)}$, $p_L(L_i = 0) = 1 - \alpha$

2. Inlier generator. If $L_i = I$, a point location x_i belonging to the line is generated as described in Section 3.

$$\boldsymbol{x}_i \sim p(\boldsymbol{x}_i | \boldsymbol{l})$$

3. Outlier generator. If $L_i = O$, an outlier (not dependent on the line) is drawn from uniform distribution, assuming finite image of area $1/\beta$.

$$\boldsymbol{x}_i \sim p_O(\boldsymbol{x}_i) = \beta(\text{const.})$$

This leads the robust joint probability of point locations and labels, given the line, to be

$$p_R(\boldsymbol{x}_i, L_i | \boldsymbol{l}) = \begin{cases} \alpha \, p(\boldsymbol{x}_i | \boldsymbol{l}) & \text{if } L_i = I \\ (1 - \alpha) \, \beta & \text{if } L_i = O \end{cases}$$
(19)

The resulting robust probability $p_R(\boldsymbol{x}_i|\boldsymbol{l})$ is obtained by marginalisation (over all values of L_i) as

$$p_R(\boldsymbol{x}_i|\boldsymbol{l}) = \sum_{L_i \in \{I,O\}} p_R(\boldsymbol{x}_i, L_i|\boldsymbol{l}) = \alpha \, p(\boldsymbol{x}_i|\boldsymbol{l}) + (1-\alpha) \, \beta \,.$$
(20)

The points are assumed to be independent, so using (16) the overall robust probability of measurements is

$$p_{R}(\mathcal{X}|\boldsymbol{l}) = n! \prod_{i=1}^{n} p_{R}(\boldsymbol{x}_{i}|\boldsymbol{l}) = n! \prod_{i=1}^{n} (\alpha \, p(\boldsymbol{x}_{i}|\boldsymbol{l}) + (1-\alpha) \, \beta) =$$

$$= n! \prod_{i=1}^{n} \left(\frac{\alpha \gamma}{\sqrt{2\pi\sigma_{e}^{2}}} e^{-\frac{d_{i}^{2}}{2\sigma_{e}^{2}}} + (1-\alpha)\beta \right).$$

$$= c_{1} \prod_{i=1}^{n} \left(e^{-\frac{d_{i}^{2}}{2\sigma_{e}^{2}} + c_{2}} \right), \qquad (21)$$

where c_1 , c_2 are some constants. Again, cost function from minus log-likelihood is constructed prior to optimisation

$$-\log\left(p_{R}(\mathcal{X}|\boldsymbol{l})\right) = -c_{1} - \sum_{i=1}^{n}\log\left(e^{\frac{-d_{i}^{2}}{2\sigma_{e}^{2}}} + c_{2}\right)$$
$$C(\boldsymbol{l}) = \sum_{i=1}^{n} -e^{2\sigma_{e}^{2}}\log\left(e^{-\frac{d_{i}^{2}}{2\sigma_{e}^{2}}} + e^{\frac{\theta^{2}}{2\sigma_{e}^{2}}}\right) = \sum_{i=1}^{n} C_{1}(d_{i}).$$
(22)

Here the constant c_2 was replaced by a threshold θ . The cost function (robust penalty) C1 is analysed in the next section.

4.1 Robust Penalty

The previous section reveals a typical property of the robust model fitting problem under Gaussian noise: the error (d_i in the case of line fitting) is modelled using a mixture of normal and constant probability density. The mixture p.d.f and its negative logarithm is

$$p(d_i) = \alpha \mathcal{N}(d_i; 0, \sigma_e) + (1 - \alpha)\beta, \quad -\log\left(p(d_i)\right) = -\log\left(\frac{\alpha}{\sqrt{2\pi\sigma_e^2}}e^{\frac{-d_i^2}{2\sigma_e^2}} + (1 - \alpha)\beta\right)$$
(23)

where α is a mixing coefficients. Example is in Figure 1.

There is an important value of d_i on the intersection of both densities (i.e. the probability of both processes is the same), denoted as a threshold θ .

$$\frac{\alpha}{\sqrt{2\pi\sigma_e^2}}e^{\frac{-\theta^2}{2\sigma_e^2}} = (1-\alpha)\beta \quad \Rightarrow \quad \theta = \sqrt{-\log\left(\frac{(1-\alpha)\beta}{\alpha}\sqrt{2\pi\sigma_e^2}\right)2\sigma_e^2} \tag{24}$$

Usually, the threshold is used to parametrise the mixture, and the Gaussian variance σ_e is assumed approx $\sigma_e \in (0.1\theta, 0.5\theta)$ (the variance affects only the curvature of the penalty function near the threshold). Then the robust penalty function after removing some constants is

$$C_1(d_i) = -2\sigma_e^2 \log\left(e^{\frac{-d_i^2}{2\sigma_e^2}} + e^{\frac{-\theta^2}{2\sigma_e^2}}\right).$$
 (25)



Fig. 1: Mixture of a Gaussian and a constant probability density. (a) Probability density function and (b) its negative logarithm.



Fig. 2: Approximation of a robust penalty. (a) penalty function C_1 (26), (b) likelihood function L_1 (28).

This function can be approximated by two segments, one quadratic and one constant,

$$C_1(d_i) \approx \begin{cases} d_i^2 & \text{if } |d_i| < \theta\\ \theta^2 & \text{if } |d_i| > \theta \end{cases}$$
(26)

The original problem is then solved by a numeric minimisation of $\sum C_1(d_i)$. Alternatively, the negative of $C_1(d_i)$ can be used for maximisation, i.e. (with a constant shift that do not affect optimisation),

$$L_1(d_i) = 1 - \frac{C_1(d_i)}{\theta^2}, \qquad (27)$$

which is then approximated as

$$L_1(d_i) \approx \begin{cases} 1 - \frac{d_i^2}{\theta} & \text{if } |d_i| < \theta \\ 0 & \text{if } |d_i| > \theta \end{cases}$$
(28)

Both approximations are demonstrated in Figure 2. Then the original problem is solved by a numeric maximisation of $\sum L_1(d_i)$.